TOSHIBA Field Effect Transistor Silicon P Channel MOS Type ($L^2-\pi$ -MOSV)

2SJ512

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• Low drain-source ON resistance : $RDS(ON) = 1.0 \Omega \text{ (typ.)}$

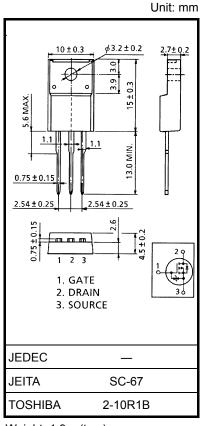
• High forward transfer admittance : $|Y_{fs}| = 3.7 \text{ S (typ.)}$

• Low leakage current $: I_{DSS} = -100 \,\mu\text{A} \,(\text{max}) \,(V_{DS} = -250 \,\text{V})$

• Enhancement mode : $V_{th} = -1.5 \sim -3.5 \text{ V (V}_{DS} = -10 \text{ V, I}_{D} = -1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

| Characteris | stics | Symbol | Rating | Unit | |
|--|----------------|------------------|---------|------|--|
| Drain-source voltage | | V_{DSS} | -250 | V | |
| Drain-gate voltage (R _{GS} = 20 kΩ) | | V_{DGR} | -250 | V | |
| Gate-source voltage | | V _{GSS} | ±20 | V | |
| Drain current | DC (Note 1) | ΙD | -5 | Α | |
| | Pulse (Note 1) | I _{DP} | -20 | Α | |
| Drain power dissipation | n (Tc = 25°C) | P _D | 30 | W | |
| Single pulse avalanche energy (Note 2) | | E _{AS} | 155 | mJ | |
| Avalanche current | | I _{AR} | -5 | Α | |
| Repetitive avalenche energy (Note 3) | | E _{AR} | 3.0 | mJ | |
| Channel temperature | | T _{ch} | 150 | °C | |
| Storage temperature ra | ange | T _{stg} | -55~150 | °C | |



Weight: 1.9 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

| Characteristics | Symbol | Max | Unit |
|--|------------------------|------|------|
| Thermal resistance, channel to case | R _{th (ch-c)} | 4.16 | °C/W |
| Thermal resistance, channel to ambient | R _{th (ch-a)} | 62.5 | °C/W |

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = -50 V, T_{ch} = 25°C (initial), L = 10.5 mH, R_G = 25 Ω , I_{AR} = -5 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



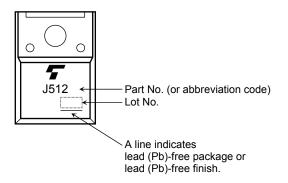
Electrical Characteristics (Ta = 25°C)

| Charac | cteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|---------------|----------------------|---|------|------|------|------|
| Gate leakage cu | ırrent | I _{GSS} | V _{GS} = ±16 V, V _{DS} = 0 V | _ | _ | ±10 | μΑ |
| Drain cut-off cu | rrent | I _{DSS} | V _{DS} = -250 V, V _{GS} = 0 V | _ | _ | -100 | μΑ |
| Drain-source br voltage | reakdown | V (BR) DSS | I _D = -10 mA, V _{GS} = 0 V | -250 | _ | _ | V |
| Gate threshold v | /oltage | V_{th} | $V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$ | -1.5 | _ | -3.5 | V |
| Drain-source O | N resistance | R _{DS (ON)} | $V_{GS} = -10 \text{ V}, I_D = -2.5 \text{ A}$ | _ | 1.0 | 1.25 | Ω |
| Forward transfer | r admittance | Y _{fs} | V _{DS} = -10 V, I _D = -2.5 A | 1.8 | 3.7 | _ | S |
| Input capacitano | ce | C _{iss} | | _ | 800 | _ | |
| Reverse transfer capacitance | | C _{rss} | $V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ | _ | 80 | _ | pF |
| Output capacitance | | Coss | | _ | 250 | _ | |
| Switching time | Rise time | t _r | V_{GS}^{OV} V_{GS}^{OV} $V_{DD} = -100V$ $V_{DD} = -100V$ | _ | 16 | _ | |
| | Turn-on time | t _{on} | | _ | 35 | _ | |
| | Fall time | t _f | | _ | 9 | _ | ns |
| | Turn-off time | t _{off} | Duty $\leq 1\%$, $t_{\mathbf{W}} = 10 \mu \text{s}$ | _ | 70 | _ | |
| Total gate charge (Gate-source plus gate-drain) | | Qg | $V_{DD} \approx -200 \text{ V, V}_{GS} = -10 \text{ V,}$ $I_{D} = -5 \text{ A}$ | _ | 22 | | nC |
| Gate-source charge | | Q _{gs} | | _ | 14 | _ | |
| Gate-drain ("miller") charge | | Q_{gd} | | _ | 8 | _ | |

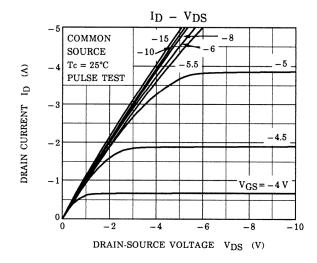
Source-Drain Ratings and Characteristics (Ta = 25°C)

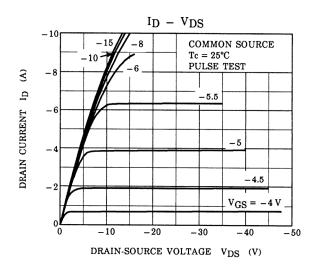
| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|------------------|---|-----|------|-----|------|
| Continuous drain reverse current (Note 1) | I _{DR} | _ | _ | _ | -5 | Α |
| Pulse drain reverse current (Note 1) | I _{DRP} | _ | _ | _ | -20 | Α |
| Forward voltage (diode) | V _{DSF} | I _{DR} = -5 A, V _{GS} = 0 V | _ | _ | 2.0 | V |
| Reverse recovery time | t _{rr} | I _{DR} = -5 A, V _{GS} = 0 V | l | 205 | 1 | ns |
| Reverse recovery charge | Q _{rr} | dI _{DR} / dt = 100 A / μs | _ | 2.1 | _ | μC |

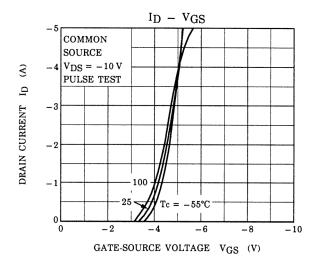
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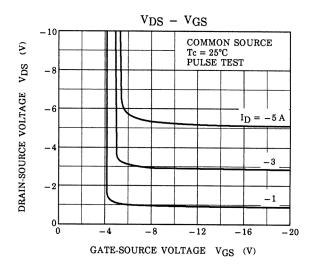


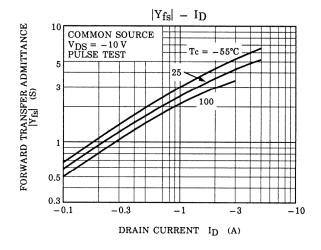
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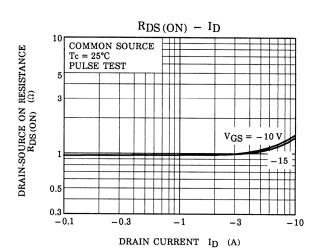


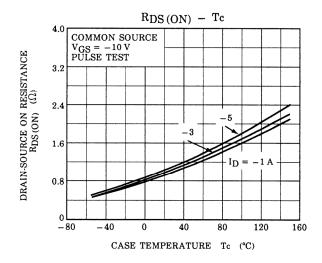


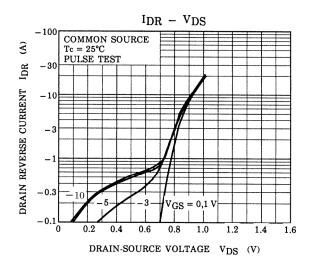


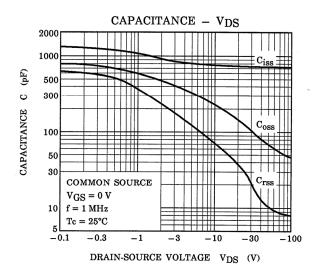


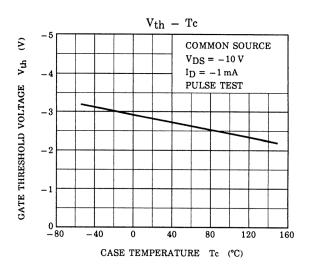


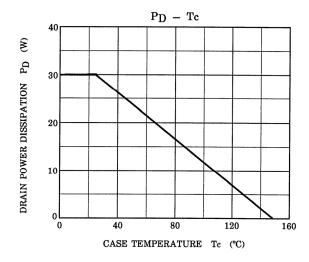


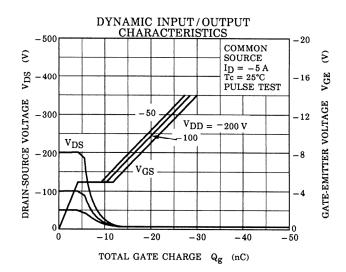


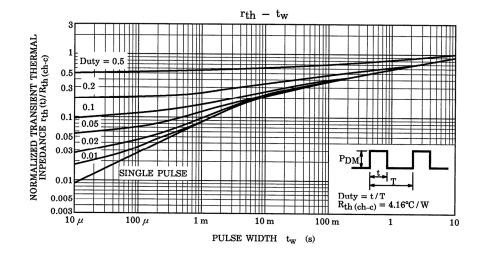


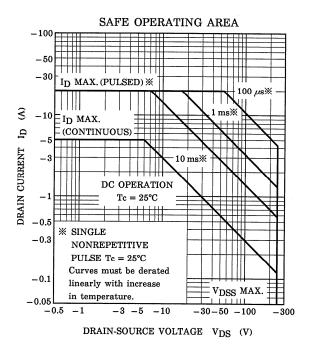


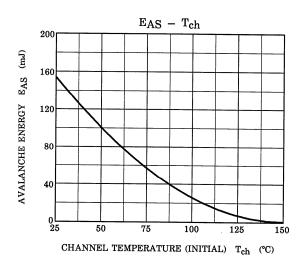


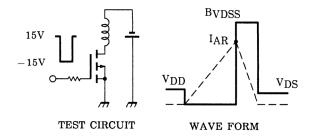












$$\begin{array}{ll} R_G\!=\!25\Omega \\ V_{DD}\!=\!-50V,\; L\!=\!10.5mH \end{array} \quad E_{AS}\!=\!\frac{1}{2}\cdot L\cdot I^2\cdot (\frac{B_{VDSS}}{B_{VDSS}\!-\!V_{DD}})$$

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